Form PTO-1449 US Dept. of Commerce (REV. 8-83) PATENT & TRADEMARK OFFICE			ATTY DOCKET NO. 124421			APPLICATION NO. New U.S. National Stage of PCT/JP03/013725					
INFORMATION DISCLOSURE STATEMENT								0/5	4121		
(Use several sheets if necessary)				APPLICANTS Masaki HIRAKATA et al.							
		@/30/05		FILING DATE June 30, 2005				GROUP 2823			
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INFORMATION DISCLOSURE STATEMENT										
(Use several sheets if necessary)			APPLICANTS Masaki HIRAKATA et al.							
	9/13/05			FILING DATE June 30, 2005			GROUP 2823			
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Form PTO-1449 US Dept. of Com (REV. 1/06) PATENT & TRADEMARK OF INFORMATION DISCLOSURE STATEMENT			ATTY DOCKET NO. 124421		APPLICATION NO. 10/541,213					
(Use several sheets if necessary)			•	APPLICANT(S) Masaki HIRAKATA et al.						
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